捷多邦,专业PCB打样**\$N54HC可244**出**\$N74HCT244** OCTAL BUFFERS AND LINE DRIVERS WITH 3-STATE OUTPUTS

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- Inputs Are TTL-Voltage Compatible
- 3-State Outputs Drive Bus Lines or Buffer Memory Address Registers
- High-Current Outputs Drive up to 15 LSTTL Loads
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

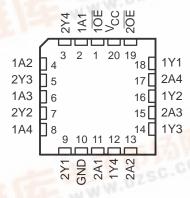
These octal buffers and line drivers are designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. The 'HCT244 are organized as two 4-bit buffers/drivers with separate output-enable (OE) inputs. When OE is low, the device passes noninverted data from the A inputs to the Y outputs. When OE is high, the outputs are in the high-impedance state.

The SN54HCT244 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HCT244 is characterized for operation from –40°C to 85°C.

SN54HCT244 . . . J OR W PACKAGE SN74HCT244 . . . DB, DW, N, OR PW PACKAGE (TOP VIEW)

1OE	1	U	20] V _{CC}
1A1	2		19	20E
2Y4	3		18] 1Y1
1A2	4		17	2A4
2Y3			16	1Y2
1A3	6		15	2A3
2Y2	7		14	1Y3
1A4	8		13	2A2
2Y1	9		12	1Y4
GND	10)	11	2A1

SN54HCT244 . . . FK PACKAGE (TOP VIEW)



FUNCTION TABLE (each buffer/driver)

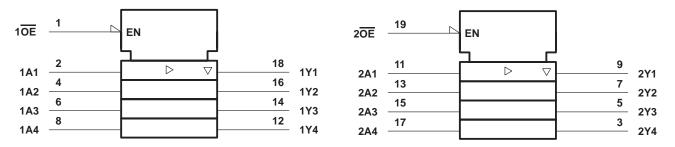
, ,		
INP	UTS	OUTPUT
OE	Α	Y
L	Н	Н
L	L	L
Н	X	Z

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SN54HCT244, SN74HCT244 OCTAL BUFFERS AND LINE DRIVERS WITH 3-STATE OUTPUTS

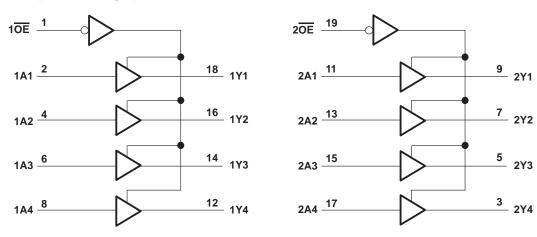
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logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range‡

Supply voltage range, V _{CC}		–0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (se	ee Note 1)	±20 mA
Output clamp current, IOK (VO < 0 or VO > VCO	c) (see Note 1)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})		±35 mA
Continuous current through V _{CC} or GND		±70 mA
Package thermal impedance, θ_{JA} (see Note 2):	DB package	115°C/W
	DW package	97°C/W
	N package	67°C/W
	PW package	128°C/W
Storage temperature range, T _{stg}		–65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.



^{2.} The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

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recommended operating conditions

			SN54HCT244			SN74HCT244			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
Vcc	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	V _{CC} = 4.5 V to 5.5 V	2			2			V
V _{IL}	Low-level input voltage	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	0		0.8	0		0.8	V
٧ _I	Input voltage		0		VCC	0		VCC	V
٧o	Output voltage		0		VCC	0		VCC	V
t _t	Input transition (rise and fall) time		0		500	0		500	ns
TA	Operating free-air temperature		-55		125	-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V	T _A = 25°C			SN54HCT244		SN74HCT244		UNIT
PARAMETER			VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
Vou	VI = VIH or VIL	I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		V
VOH	AI = AIH OL AIL	$I_{OH} = -6 \text{ mA}$	4.5 V	3.98	4.3		3.7		3.84		٧
Voi	VI = VIH or VIL	I _{OL} = 20 μA	4.5 V		0.001	0.1		0.1		0.1	V
VOL	AI = AIH OL AIL	I _{OL} = 6 mA	4.5 V		0.17	0.26		0.4		0.33	\ \ \
ΙĮ	$V_I = V_{CC}$ or 0		5.5 V		±0.1	±100		±1000		±1000	nA
I _{OZ}	$V_O = V_{CC}$ or 0,	$V_I = V_{IH}$ or V_{IL}	5.5 V		±0.01	±0.5		±10		±5	μΑ
ICC	$V_I = V_{CC}$ or 0,	IO = 0	5.5 V			8		160		80	μΑ
Δl _{CC} †	One input at 0.5 V one of the of the order o		5.5 V		1.4	2.4		3		2.9	mA
Ci			4.5 V to 5.5 V		3	10		10		10	pF

[†] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то		T,	Վ = 25° C	;	SN54H	CT244	SN74H	CT244	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
+ .	А	V	4.5 V		15	28		42		35	ne	
^t pd	A	'	5.5 V		13	25		38		32	ns	
	ŌĒ	Y	4.5 V		21	35		53		44	no	
t _{en}		ī	5.5 V		19	32		48		40	ns	
.	ŌĒ		V	4.5 V		19	35		53		44	20
^t dis		ī	5.5 V		18	32		48		40	ns	
4.			V	4.5 V		8	12		18		15	no
t _t		^Y	5.5 V		7	11		16		14	ns	



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switching characteristics over recommended operating free-air temperature range, C_L = 150 pF (unless otherwise noted) (see Figure 1)

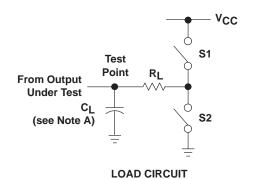
PARAMETER	FROM	то	Vaa	T,	ղ = 25°C	;	SN54H	CT244	SN74H	CT244	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
	А	V	4.5 V		21	45		68		56	20	
^t pd	A	Ť	5.5 V		18	40		61		51	ns	
	ŌĒ	ŌĒ Y	4.5 V		25	52		79		65	20	
^t en			•	5.5 V		22	47		71		59	ns
t _t			V	4.5 V		17	42		63		53	no
		Ť	5.5 V		14	38		57		48	ns	

operating characteristics, $T_A = 25^{\circ}C$

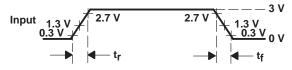
	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance per buffer/driver	No load	40	pF

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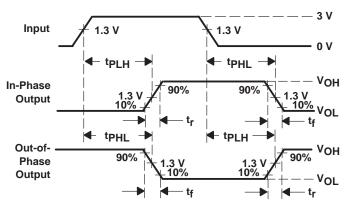
PARAMETER MEASUREMENT INFORMATION

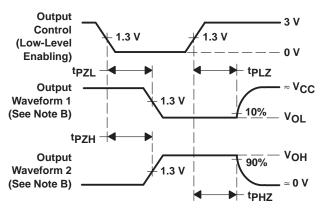


PARAI	PARAMETER		CL	S1	S2
	ten tPZH 1 kΩ 50 pF or 150 pF		Open	Closed	
чen				Closed	Open
4	tPHZ	1 k Ω	50 pF	Open	Closed
^t dis	tPLZ	1 K22	30 pr	Closed	Open
t _{pd} or	t _t	_	50 pF or 150 pF	Open	Open



VOLTAGE WAVEFORM INPUT RISE AND FALL TIMES





VOLTAGE WAVEFORMS PROPAGATION DELAY AND OUTPUT RISE AND FALL TIMES

VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS

NOTES: A. C_L includes probe and test-fixture capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_f = 6 ns.
- D. The outputs are measured one at a time with one input transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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